

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S322	6	S321 and ( ((different or higher or lower or greater) near3 threshold) with thickness)	US-PGPUB; USPAT	OR	ON	2006/04/17 11:49
S215	7	S214 not S213	US-PGPUB; USPAT	OR	ON	2006/04/17 11:49
S325	8	S324 and (@ad<"20040319" or @rlad<"20040319")	US-PGPUB; USPAT	OR	ON	2006/04/17 11:50
S324	9	S323 not S322	US-PGPUB; USPAT	OR	ON	2006/04/17 11:51
S327	23	S326 and (@ad<"20040319" or @rlad<"20040319")	US-PGPUB; USPAT	OR	ON	2006/04/17 11:55
S326	25	fin\$1fet and ( (gate adj (dielectric or insulator or insulating or insulation)) with (thickness near different ))	US-PGPUB; USPAT	OR	ON	2006/04/17 11:55
S269	21	S268 and (@ad<"20040319" or @rlad<"20040319")	US-PGPUB; USPAT	OR	ON	2006/04/17 11:55
S328	22	S327 not S323	US-PGPUB; USPAT	OR	ON	2006/04/17 11:56
S309	0	S308 not (S305 or S301 or S285 or S281 or S277 or S272 or S269 or S270)	US-PGPUB; USPAT	OR	ON	2006/04/17 12:18
S323	10	S321 and ( (gate adj (dielectric or insulator or insulating or insulation)) with (thicker ))	US-PGPUB; USPAT	OR	ON	2006/04/25 15:56
S331	0	((each or individual) adj fin) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	US-PGPUB; USPAT	OR	ON	2006/04/25 15:57
S333	0	((each or individual) adj fin) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) with (thickness ))	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 15:58
S334	8	( fin with (gate adj (dielectric or insulator or insulating or insulation or oxide)) with (thickness ))	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 15:59
S330	0	((each or individual) adj fin) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) with (thickness ))	US-PGPUB; USPAT	OR	ON	2006/04/25 16:02
S332	1	((different adj fin) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	US-PGPUB; USPAT	OR	ON	2006/04/25 16:03
S339	4	S338 and (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) )	US-PGPUB; USPAT	OR	ON	2006/04/25 16:05
S341	3	S340 and (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) )	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 16:06
S345	0	S344 not S343	US-PGPUB; USPAT	OR	ON	2006/04/25 16:09
S344	2	((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top) and S342	US-PGPUB; USPAT	OR	ON	2006/04/25 16:09
S343	2	((different adj thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top) and S342	US-PGPUB; USPAT	OR	ON	2006/04/25 16:24
S346	2	((different near2 thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top) and S342	US-PGPUB; USPAT	OR	ON	2006/04/25 16:25
S350	0	S349 not S343	US-PGPUB; USPAT	OR	ON	2006/04/25 16:26
S349	2	((different near3 thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top) and S348	US-PGPUB; USPAT	OR	ON	2006/04/25 16:26

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S34 7	2	( (different near3 thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top) and S342	US-PGPUB; USPAT	OR	ON	2006/04/25 16:26
S35 2	3	((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not (sidewall and top) ) and S348	US-PGPUB; USPAT	OR	ON	2006/04/25 16:31
S35 1	3	( (different near3 thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not (sidewall and top) ) and S348	US-PGPUB; USPAT	OR	ON	2006/04/25 16:31
S35 8	0	S357 not S352	US-PGPUB; USPAT	OR	ON	2006/04/25 16:32
S35 6	0	S354 not S352	US-PGPUB; USPAT	OR	ON	2006/04/25 16:32
S35 7	3	((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not (sidewall and top) ) and S353	US-PGPUB; USPAT	OR	ON	2006/04/25 17:19
S36 1	0	((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top ) and S359	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 17:21
S36 0	0	((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not (sidewall and top) ) and S359	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 17:21
S36 3	8	((multi or multiple) adj (channel) ) with ((fin adj fet) or fin\$1fet) )	US-PGPUB; USPAT	OR	ON	2006/04/25 17:27
S36 2	7	( multi\$1finfet or ((multi or multiple) adj ((fin adj fet) or fin\$1fet) ) or multiple\$1finfet)	US-PGPUB; USPAT	OR	ON	2006/04/25 17:27
S36 6	0	( different with thickness with (gate adj (dielectric or insulator or insulating or insulation or oxide)) ) and S364	US-PGPUB; USPAT	OR	ON	2006/04/25 17:28
S36 5	33	( different with thickness with (gate adj (dielectric or insulator or insulating or insulation or oxide)) ) and S337	US-PGPUB; USPAT	OR	ON	2006/04/25 17:28
S35 4	3	( (different near3 thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not (sidewall and top) ) and S353	US-PGPUB; USPAT	OR	ON	2006/04/25 17:28
S36 7	1	((multiple\$1channel or ((several) adj (channel) ) or multi\$1channel) with ((fin adj fet) or fin\$1fet) )	US-PGPUB; USPAT	OR	ON	2006/04/25 17:29
S36 4	8	((multiple\$1channel or ((multi or multiple) adj (channel) ) or multi\$1channel) with ((fin adj fet) or fin\$1fet) )	US-PGPUB; USPAT	OR	ON	2006/04/25 17:29
S33 7	33	S336 and (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) )	US-PGPUB; USPAT	OR	ON	2006/04/26 17:43
S36 9	9	( fins with (thicknesses or thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	US-PGPUB; USPAT	OR	OFF	2006/04/26 17:49
S37 2	18	S371 and (@ad<"20040319" or @rlad<"20040319")	US-PGPUB; USPAT	OR	ON	2006/04/26 17:50
S37 1	20	S370 not S369	US-PGPUB; USPAT	OR	ON	2006/04/26 17:50
S37 4	4	S373 not S372	US-PGPUB; USPAT	OR	ON	2006/04/26 17:55
S37 3	4	( fin with (thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top)	US-PGPUB; USPAT	OR	ON	2006/04/26 17:55
S37 6	2	( fin with ((thicknesses or thickness) near different) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 17:56

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S37 0	23	( fin with ((thicknesses or thickness) near different) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	US-PGPUB; USPAT	OR	ON	2006/04/26 17:56
S37 7	2	(( (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) with ((thicknesses or thickness) near different) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 17:57
S37 8	4	(( (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) with ((thicknesses or thickness) near different) with (gate adj (dielectric or insulator or insulating or insulation or oxide)))	US-PGPUB; USPAT	OR	ON	2006/04/26 17:58
S38 1	0	S379 and ((thickness) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top)	US-PGPUB; USPAT	OR	ON	2006/04/26 17:59
S38 0	0	S379 and ((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top)	US-PGPUB; USPAT	OR	ON	2006/04/26 17:59
S37 5	0	(( fin with (thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) not top)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 17:59
S37 9	14	(( (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) with (array or cell) with (periphery or peripheral))	US-PGPUB; USPAT	OR	ON	2006/04/26 18:09
S38 2	7	(( (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) with ((different or higher or lower) near2 threshold) )	US-PGPUB; USPAT	OR	ON	2006/04/26 18:15
S38 4	3	(( (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) with ((different or higher or lower) near2 (gate adj (dielectric or insulator or insulating or insulation or oxide)) ) )	US-PGPUB; USPAT	OR	ON	2006/04/26 18:16
S38 5	2	(( (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) with ((different or higher or lower) near2 (gate adj (dielectric or insulator or insulating or insulation or oxide)) ) )	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 18:19
S38 8	1	(fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) and ((thicker or thinner) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 18:20
S38 7	0	(fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) and ((thicker or thinner) near2 (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 18:20
S38 6	2	(fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) and ((different or higher or lower) near2 (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 18:21
S38 9	0	((("2nd" or second or several or many or "plurality") adj (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) ) and ((different or higher or lower) near2 (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 18:22
S39 2	12	((("2nd" or second or several or many or "plurality") adj (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) ) and ((different or higher or lower) with (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	US-PGPUB; USPAT	OR	ON	2006/04/26 18:23
S39 1	0	((("2nd" or second or several or many or "plurality") adj (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) ) ) and ((different or higher or lower) near3 (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	US-PGPUB; USPAT	OR	ON	2006/04/26 18:23

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S39 0	0	((("2nd" or second or several or many or "plurality") adj (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet)) ) ) and ((different or higher or lower) near2 (gate adj (dielectric or insulator or insulating or insulation or oxide)) )	US-PGPUB; USPAT	OR	ON	2006/04/26 18:23
S39 6	4	S395 and ( (gate adj (oxide or dielectric or insulator or insulating or insulation) ) with (thicker or thinner))	US-PGPUB; USPAT	OR	ON	2006/04/30 12:44
S36 8	3	(several adj fin) and (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) )	US-PGPUB; USPAT	OR	ON	2006/04/30 12:55
S39 9	24	(silicide with (capping or cap) ) and (fin\$1fet or (fin near3 (fet or (field adj effect) or transistor or mosfet or misfet or igfet) ) )	US-PGPUB; USPAT	OR	ON	2006/04/30 12:56